



CERTIFICATE



Of Best Paper Award

THIS CERTIFICATE IS PROUDLY PRESENTED TO

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Georgia Institute of Technology, Atlanta, USA
Bilkent University, Ankara, Turkey

Instruction-level Reliability Improvement for Embedded Systems

or participating to the 2020 IEEE international conference
on Design & Test of integrated micro & nano-Systems (DTS'2020),
which was held in Tunisia June 8 -10, 2020. (Virtual Event)

Tunisia, June 10st 2020



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